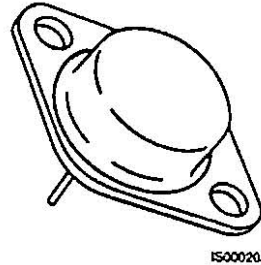


**Description**

These devices are n-channel, enhancement mode, power MOSFETs designed especially for high voltage, high speed applications, such as off-line switching power supplies, UPS, AC and DC motor controls, relay and solenoid drivers.

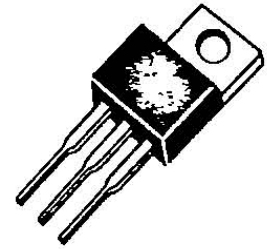
- $V_{GS}$  Rated at  $\pm 20V$
- Silicon Gate for Fast Switching Speeds
- $I_{DSS}$ ,  $V_{DS(on)}$ ,  $S_{OA}$  and  $V_{GS(th)}$  Specified at Elevated Temperature
- Rugged

TO-204AA



IS00020F

TO-220AB



IS00010F

IRF340  
 IRF341  
 IRF342  
 IRF343  
 MTM8N35  
 MTMT8N40

IRF740  
 IRF741  
 IRF742  
 IRF743

**Maximum Ratings**

Symbol	Characteristic	Rating IRF340/342 IRF740/742 MTM8N40	Rating IRF341/343 IRF741/743 MTM8N35	Unit
$V_{DSS}$	Drain to Source Voltage	400	350	V
$V_{DGR}$	Drain to Gate Voltage $R_{GS}=1.0M \Omega$	400	350	V
$V_{GS}$	Gate to Source Voltage	$\pm 20$	$\pm 20$	V
$T_J, T_{stg}$	Operating Junction Temperature Storage Temperature	-55 to +150	-55 to +150	
$T_L$	Maximum Lead Temperature for Soldering Purposes, 1/8" From Case for 5S	275	275	

**Maximum On-State Characteristics**

		IRF340/341 IRF740/741	IRF342/343 IRF742/743	MTM8N35 MTM8N40	
$R_{DS(on)}$	Static Drain-to-Source On Resistance	0.55	0.80	0.55	$\Omega$
$I_D$	Drain Current				A
	Continuous	10	8	8	
	Pulsed	40	32	48	

**Maximum Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.0	1.0	0.83	/W
$P_D$	Total Power Dissipation at $T_c=25$	125	125	150	W

**Notes**

For Information concerning connection diagram and package outline, refer to Section 7.



**IRF340-343/IRF740-743 T-39-13**  
**MTM8N35/8N40**  
**N-Channel Power MOSFETs**  
**10A, 350V/400V**

**Electrical Characteristics** (Tc=25 unless otherwise noted)

Symbol	Characteristic	Min	Max	Unit	Test Conditions
<b>Off Characteristics</b>					
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage1 IRF340/342/740/742 Irf341/343/741/743			V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
		400			
		350			
I <sub>DSS</sub>	Zero Gate Voltage Drain Current		250	μA	V <sub>DS</sub> =Rated V <sub>DSS</sub> , V <sub>GS</sub> =0V
			1000	μA	V <sub>DS</sub> =0.8 x Rated V <sub>ds</sub> , V <sub>GS</sub> =0V, Tc=125
I <sub>GSS</sub>	Gate-Body Leakage Current IRF340-343 IRF740-743			nA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
			±100		
			±500		
<b>On Characteristics</b>					
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	4.0	V	I <sub>D</sub> =250μA, V <sub>DS</sub> =V <sub>GS</sub>
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance 2 IRF340/341/740/741 IRF342/343/742/743			Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =5.0A
			0.55		
			0.80		
g <sub>fs</sub>	Forward Transconductance	4.0		S(Ω)	V <sub>DS</sub> =10V, I <sub>D</sub> =5.0A
<b>Dynamic Characteristics</b>					
C <sub>iss</sub>	Input Capacitance		1600	pF	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V f=1.0MHz
C <sub>oss</sub>	Output Capacitance		450	pF	
C <sub>rss</sub>	Reverse Transfer Capacitance		150	pF	
<b>Switching Characteristics</b> (Tc=25, Figures 9, 10)					
td(on)	Turn-On Delay Time		35	ns	V <sub>DD</sub> =175V, I <sub>D</sub> =5.0A V <sub>GS</sub> =10V, R <sub>GEN</sub> =4.7 Ω R <sub>GS</sub> =4.7 Ω
tr	Rise Time		15	ns	
td(off)	Turn-Off Delay Time		90	ns	
tf	Fall Time		35	ns	
Qg	Total Gate Charge		60	nC	V <sub>GS</sub> =10V, I <sub>D</sub> =12A V <sub>DD</sub> =400V
<b>Symbol Characteristic</b>					
Symbol	Characteristic	TYP	Max	Unit	Test Conditions
<b>Source-Drain Diode Characteristics</b>					
V <sub>SD</sub>	Diode Forward Voltage IRF340/341/740/741 Irf342/343/742/743		2.0	V	I <sub>S</sub> =10A; V <sub>GS</sub> =0V
			1.9	V	I <sub>S</sub> =8A; V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	600		ns	I <sub>S</sub> =10A; dI <sub>S</sub> /dt=100A/μS



**IRF340-343/IRF740-743 T-39-13**  
**MTM8N35/8N40**  
**N-Channel Power MOSFETs**  
**10A, 350V/400V**

**Electrical Characteristics** (Tc=25 unless otherwise noted)

Symbol	Characteristic	Min	Max	Unit	Test Conditions
<b>Off Characteristics</b>					
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage <sup>1</sup> MTM8N40 MTM8N35			V	V <sub>GS</sub> =0V, I <sub>D</sub> =5.0mA
		400			
		350			
I <sub>DSS</sub>	Zero Gate Voltage Drain Current		0.25	mA	V <sub>DS</sub> =0.85 x Rated V <sub>DSS</sub> , V <sub>GS</sub> =0V
			2.5	mA	V <sub>DS</sub> =0.85 x Rated V <sub>DSS</sub> , V <sub>GS</sub> =0V, Tc=100
I <sub>GSS</sub>	Gate-Body Leakage Current		±500	nA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
<b>On Characteristics</b>					
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	4.5	V	I <sub>D</sub> =1.0mA, V <sub>DS</sub> =V <sub>GS</sub>
		1.5	4.0	V	I <sub>D</sub> =1.0mA, V <sub>DS</sub> =V <sub>GS</sub> Tc=100
V <sub>DS(on)</sub>	Drain-Source On-Voltage <sup>2</sup>		2.2	V	V <sub>GS</sub> =10V; I <sub>D</sub> =4.0A
			5.3	V	V <sub>GS</sub> =10V; I <sub>D</sub> =8.0A
			4.4	V	V <sub>GS</sub> =10V, I <sub>D</sub> =4.0A Tc=100
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance <sup>2</sup>		0.55	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =4.0A
g <sub>fs</sub>	Forward Transconductance	3.0		S(Ū)	V <sub>DS</sub> =10V, I <sub>D</sub> =4.0A
<b>Dynamic Characteristics</b>					
C <sub>iss</sub>	Input Capacitance		1800	pF	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V F=1.0MHz
C <sub>oss</sub>	Output Capacitance		350	pF	
C <sub>rss</sub>	Reverse Transfer Capacitance		150	pF	
<b>Switching Characteristics</b> (Tc=25, Figures 9,10) <sup>3</sup>					
t <sub>d(on)</sub>	Turn-On Delay Time		60	ns	V <sub>DD</sub> =25V, I <sub>D</sub> =4.0A V <sub>GS</sub> =10V, R <sub>GEN</sub> =50 Ω R <sub>GS</sub> =50 Ω
t <sub>r</sub>	Rise Time		150	ns	
t <sub>d(off)</sub>	Turn-Off Delay Time		200	ns	
t <sub>f</sub>	Fall Time		120	ns	
Q <sub>g</sub>	Total Gate Charge		60	nC	V <sub>GS</sub> =10V, I <sub>D</sub> =12A V <sub>DD</sub> =400V

**Notes**

1. T<sub>J</sub>=+25 to +150
2. Pulse test: Pulse width ≤80μs, Duty cycle≤1%
3. Switching time measurements performed on LEM TR-58 test equipment.

Typical Performance Curves

Figure 1 Output Characteristics

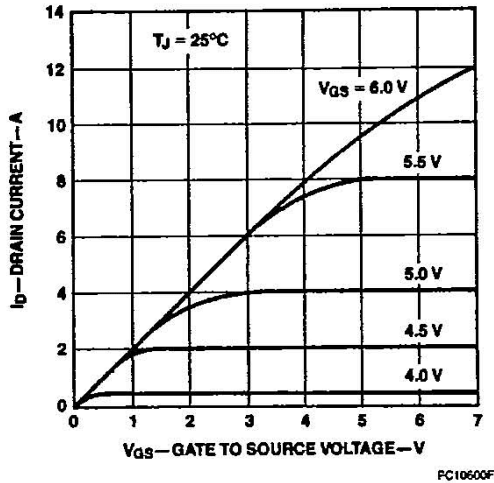


Figure 2 Static Drain to Source Resistance vs Drain Current

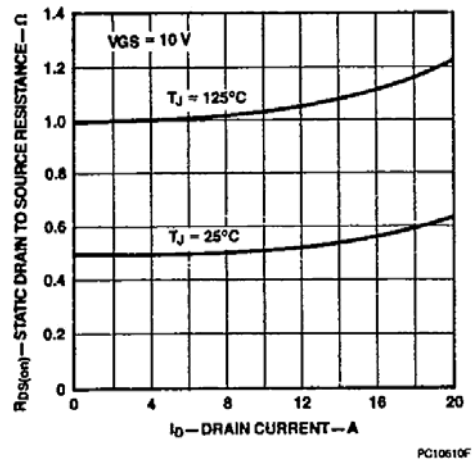


Figure 3 Transfer Characteristics

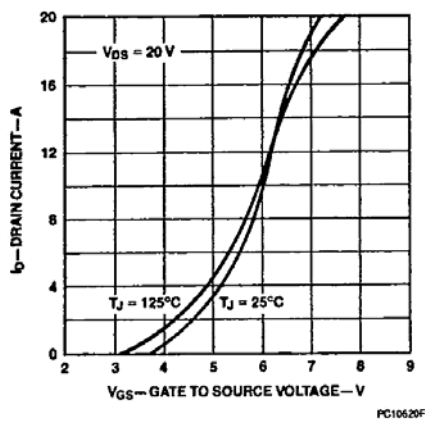


Figure 4 Temperature Variation of Gate to Source Threshold Voltage

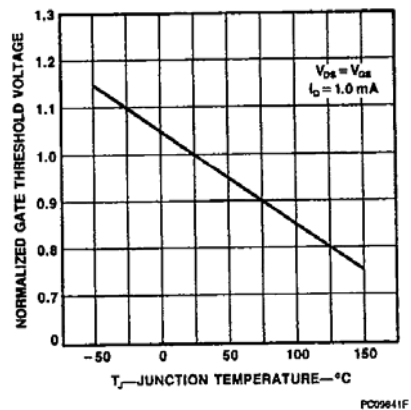


Figure 5 Capacitance vs Drain to Source Voltage

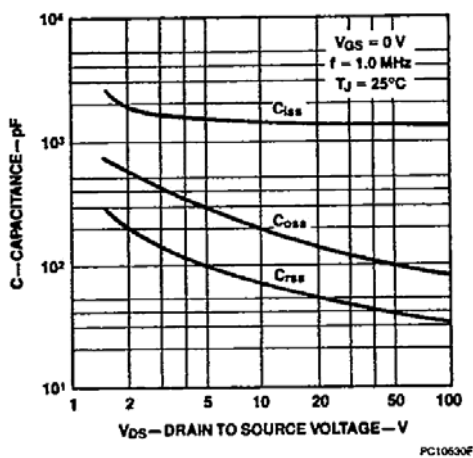
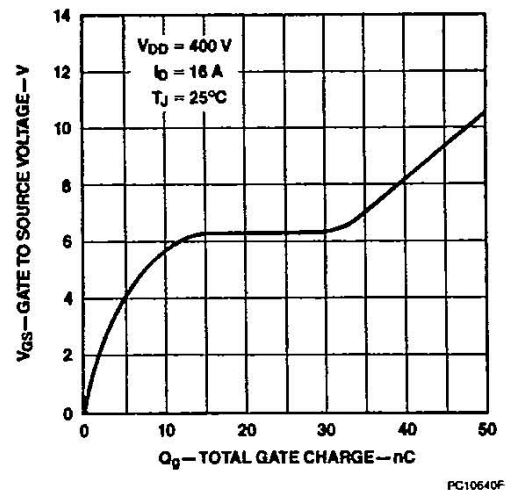
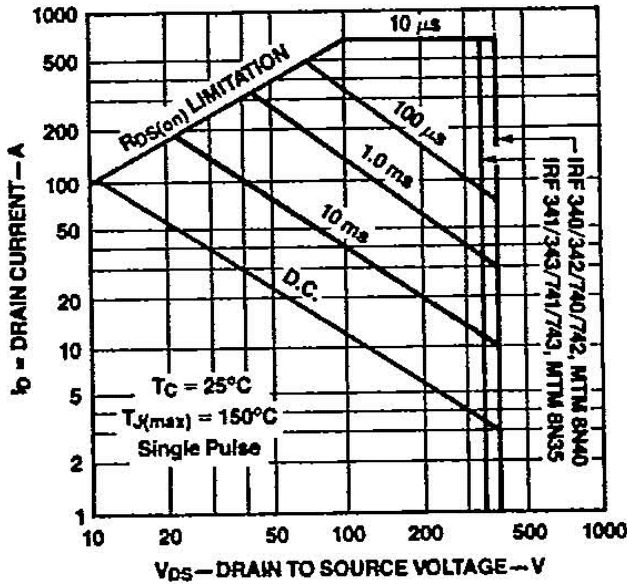


Figure 6 Gate to Source Voltage vs Total Gate Charge



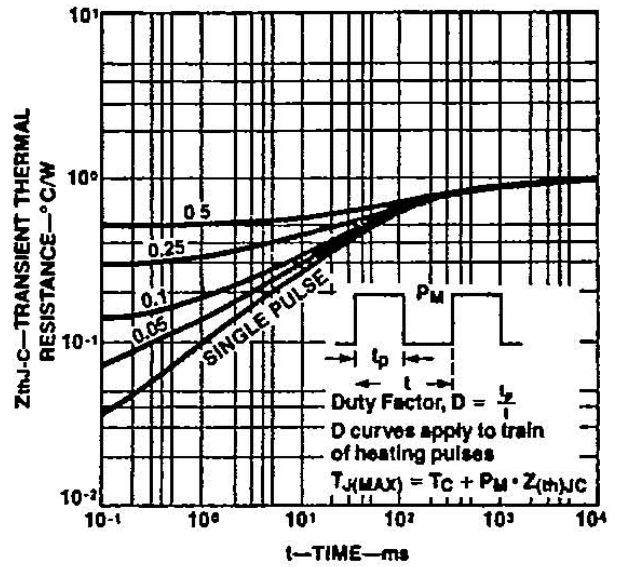
Typical Performance Curves (Cont.)

Figure 7 Forward Biased Safe Operating Area



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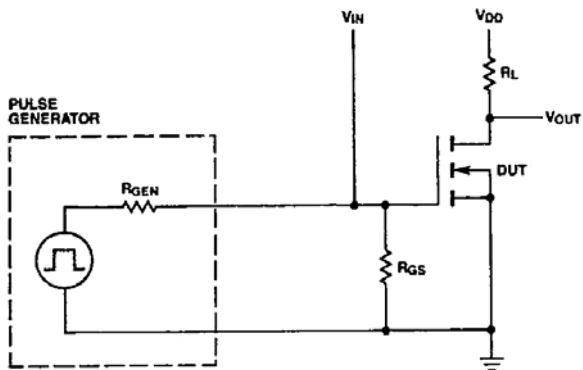
Figure 8 Transient Thermal Resistance vs Time



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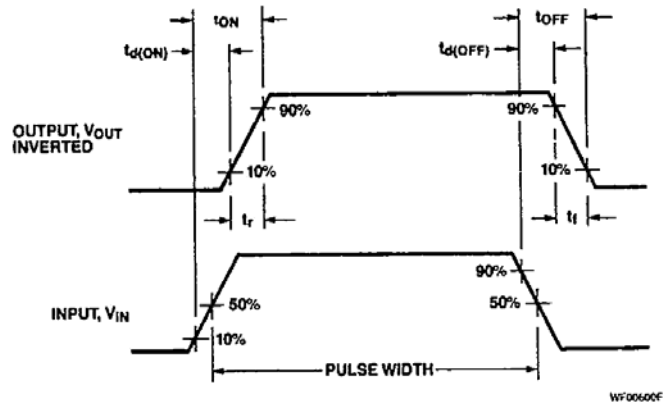
Typical Electrical Characteristics

Figure 9 Switching Test Circuit



CR04150F

Figure 10 Switching Waveforms



WF00600F